

EXspect 271 NIR backscattering sensor in compact design



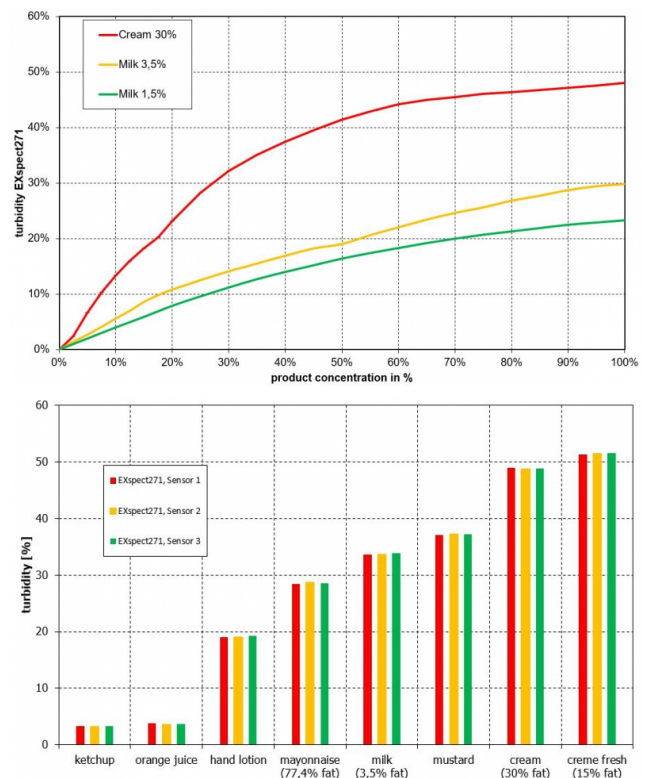
- » Compact design with integrated amplifier
- » %-turbidity or customer defined unit
- » Durable sapphire lens
- » Hygienic Design, CIP/SIP-capable
- » LED light source guarantees a durable and stable signal
- » Easy parameterization via display or software EXpert
- » Versions according EHEDG / 3-A available

EXspect 271 is a high-precision, compact NIR turbidity sensor for monitoring production processes in the food industry, e.g. in dairies, as well as in many areas of process applications with medium and high turbidity.

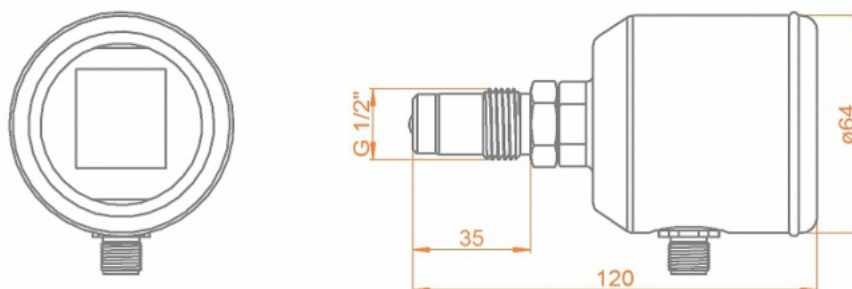
Specifications

Measuring range max.:	0-100 %turb
Resolution:	0,1 %
Accuracy:	± 1,5 % from measurement value
Reproducibility:	≤ 1 % from final value
Wavelength:	850 nm
Light source:	LED
Material:	Stainless steel 1.4435 (316L)
Surface:	Ra <0,37 µm
Lens:	Sapphire
Supply voltage:	24 V DC
Contact:	NO or NC configurable 150 mA
Input contact:	zeroing
Process connection:	Thread G1/2"
Process temperature:	-10...100 °C, 141 °C max. 2 hours (SIP cycle)
Process pressure:	max. 20 bar (290 psi)
Electrical connection:	M12 connector 5-pin or 8-pin (digital parameterizable)
Interfaces:	0/4...20 mA
Parameterization:	Software EXpert
Protection class:	IP69

Typical Measurements



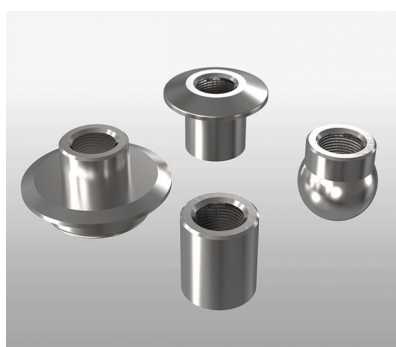
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Order code

Code	Measuring range	Delivery time
A	0...100 % turbidity	3 Weeks
Code	Material (wetted parts)	Delivery time
4435	Stainless steel 1.4435 / 316L	3 Weeks
Code	Sealing material (wetted sealings)	Delivery time
MET	Without elastomer sealing	3 Weeks
Code	Process connection	Delivery time
G12	Thread G1/2" (metallic sealing)	3 Weeks
VRN	Varivent N DN40-125 (EHEDG/3A)	3 Weeks
T15	Tri-Clamp 1,5" (EHEDG/3A)	3 Weeks
T20	Tri-Clamp 2" (EHEDG/3A)	3 Weeks
Code	Interface	Delivery time
AS	Analogue 4...20 mA / M12 5-pin	3 Weeks
AD	Analogue 4...20 mA/digital interface/M12 8-pin	3 Weeks
Code	Display	Delivery time
1	With integrated display	3 Weeks

Accessories



Weld-in socket and process adapters



Reference normal for verification - backscatter measurement